


<b>Search Notes</b>  	<b>Application/Control No.</b>  10766208	<b>Applicant(s)/Patent Under Reexamination</b>  FURUKAWA ET AL.
	<b>Examiner</b>  Le Nguyen	<b>Art Unit</b>  2174

SEARCHED			
Class	Subclass	Date	Examiner
715	745	11/19/07	lvn

SEARCH NOTES		
Search Notes	Date	Examiner
EPO, JPO. ACM library, IEEE Xplore.	11/19/07	lvn
US-PGPub, USPAT: 715/745,748,742; 705/400-411,64; 709/206.	11/19/07	lvn

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
715	745	11/19/07	lvn